



SEMI® INTERNATIONAL STANDARDS

# Standards Staff Report

October 15, 2015

R0.1





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# SEMI Global

## 2015 / 2016 Calendar of Events

Event Name		Event Details
	<b>SEMICON Europa</b> <b>Plastic Electronic Conference</b>	<b>October 6-8</b> <b>Dresden, Germany</b>
	<b>SEMICON Japan</b>	<b>December 16-18</b> <b>Tokyo</b>
	<b>European 3D Summit</b>	<b>Jan 18-20, 2016</b> <b>Grenoble, France</b>
	<b>SEMICON Korea</b> <b>LED Korea</b>	<b>Jan 27-29, 2016</b> <b>Seoul</b>
	<b>Advanced Semiconductor</b> <b>Manufacturing Conference (ASMC)</b>	<b>May 16-19, 2016</b> <b>Saratoga Spring, NY</b>
	<b>SEMICON West</b>	<b>July 12-14, 2016 (tentative)</b> <b>San Francisco, California</b>

# Global Standards Meeting Schedule

## <http://www.semi.org/en/node/9051>

As of October 15, 2015  
Please make sure most updated  
information in the above URL

- Oct 5-7, 2015  
SEMICON Europa Standards Meetings  
Dresden, Germany
- Oct. 15, 2015  
Mircostructuring Japan TC Chapter  
Meeting  
Tokyo, Japan
- Oct. 16, 2015  
Assembly & Packaging Japan TC Chapter  
Meeting  
Tokyo, Japan
- Oct. 16, 2015  
3DS-IC Japan TC Chapter Meeting  
Tokyo, Japan
- Oct. TBD, 2015  
EHS Taiwan TC Chapter Meeting  
Hsinchu Science Park Admin Building,  
Taiwan
- Nov. 1-5, 2015  
North America Standards Fall 2015  
Meetings  
San Jose, CA
- Nov 11, 2015  
FPD Materials & Components / FPD  
Metrology Japan TC Chapter Joint  
Meeting  
Tokyo, Japan
- Dec. 15-18, 2015  
SEMICON Japan Standards Meetings  
Tokyo, Japan



# NA Fall Standards Meetings

- November 1 - November 5 in San Jose, California.
- Meeting Schedule
  - MEMS / NEMS Monday, November 2
  - Traceability Monday, November 2
  - 3DS-IC Tuesday, November 3
  - Facilities & Gases Tuesday, November 3
  - Liquid Chemicals Tuesday, November 3
  - Information & Control Wednesday, November 4
  - Metrics Wednesday, November 4
  - Physical Interfaces & Carriers Wednesday, November 4
  - Photovoltaic/Photovoltaic Materials Wednesday, November 4
  - Environmental, Health & Safety Thursday, November 5
  - HB-LED Thursday, November 5
- For more information
  - <http://www.semi.org/en/node/57096>



Fall2015\_Rev06

## 開催概要

日時： 2015年12月16日（水）～ 18日（金）

会場： 東京ビッグサイト 東展示棟、会議棟

規模： 700社 1,700小間

延べ来場者： 65,000名

\*延べ来場者数は、日毎の入場登録者と出展者を含む延べ人数です。

## テーマ

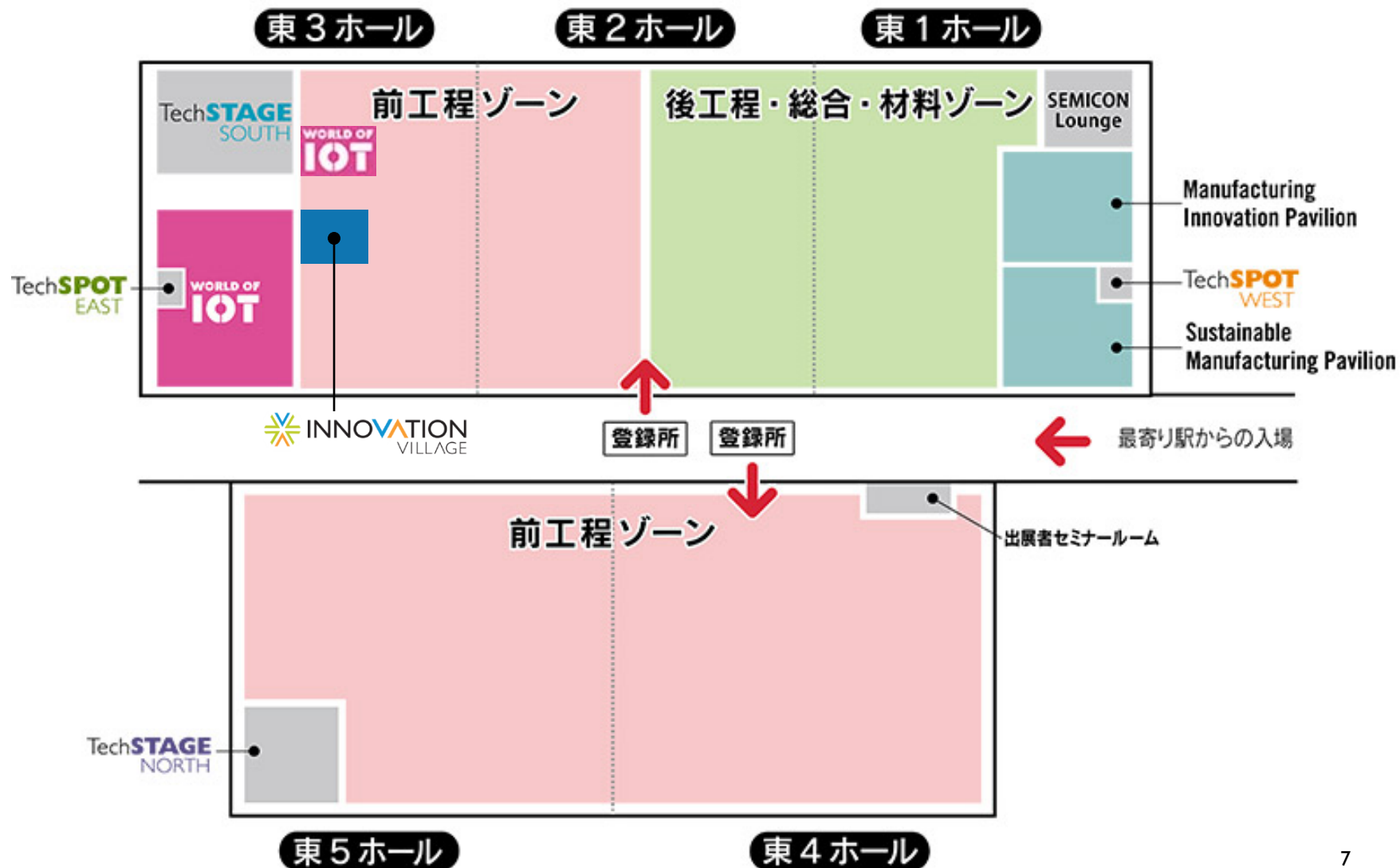


without limits

限界を突き破れ。

テクノロジーが導くわたしたちの未来、  
あるいは、わたしたちが導くテクノロジーの未来に、  
限界はありません。

# レイアウトプラン



# SEMICON<sup>®</sup>Japan Super**THEATER**

世界のエグゼクティブが登壇する基調講演級の無料プログラム

12月16日	12月17日	12月18日
オープニング キーノート	米国大使館協賛 ITフォーラム	リソグラフィー ビジネス フォーラム
半導体 エグゼクティブ フォーラム	Digital Society フォーラム	製造イノベーション フォーラム
SEMIマーケット フォーラム	Smart Life & Smart Car フォーラム	GSA協賛 グランドフィナーレ パネル



# オープニングキーノート

- IoTがもたらす未来 -



富士通（株） 代表取締役会長  
山本 正已



日本タタ・コンサルタンシー・サービスズ（株）  
代表取締役社長 アムル ラクシュミナラヤナン



楽天（株）  
執行役員 兼 楽天技術研究所長 森 正弥

# 半導体エグゼクティブフォーラム

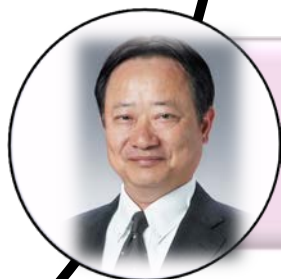
- 限界を突き破れ -



Micron Technology, Inc., President,  
Mark Adams



ルネサスエレクトロニクス（株）  
執行役員 兼 CTO 日高 秀人



ソニー（株）業務執行役員 SVP デバイス  
ソリューション事業本部副本部長 清水 照士

# 技術セミナー:100時間を上回る情報発信

展示会場から最先端技術情報を発信。全セッション無料

12月16日		12月17日		12月18日	
Tech <b>STAGE</b> SOUTH	Tech <b>STAGE</b> NORTH	Tech <b>STAGE</b> SOUTH	Tech <b>STAGE</b> NORTH	Tech <b>STAGE</b> SOUTH	Tech <b>STAGE</b> NORTH
パワー デバイス (1)	MEMS・ センサ(1)	先端 リソグラ フィー (1)	半導体 中古	IoT 未来	先端 デバイス (1)
パワー デバイス (2)	MEMS・ センサ(2)	先端 リソグラ フィー (2)	若手エン ジニア	TSV/2.5D /3D	先端 デバイス (2)
IoT/IV ジョイント 企画	テスト	特別	DFM	パッ ケー ジング	学生 企画



# SEMICON Japan期間中 スタンダード関連スケジュール

- Dec. 15 (Tue.) ----@SEMI Japan Office
  - 11:30-13:00 Gases/Facilities (Joint)
  - 14:30-19:00 JRSC
- Dec. 16 (Wed.)
  - 10:00-12:00 Liquid Chemicals
  - 14:00-17:00 PI&C
- Dec. 17 (Thu.)
  - 08:30-12:30 Silicon Wafer
  - 13:30-16:30 ISC
  - 17:00-18:30 Standards Reception (Friendship Party)
- Dec. 18 (Fri.)
  - 10:00-12:00 Traceability
  - 10:00-17:00 I&C
  - TBD EHS



2015\_Std会議棟  
割当て1002

Check the meeting schedule plan  
in the separate file and confirm  
your TC Chapter and task force  
meetings

# JRSC Highlight

- 3DS-IC Japan TC Chapter
  - approved by JRSC on Aug. 31
  - Held Kick-off Meeting and workshop on Sep. 7
  - Workshop, drew more than 60 attendees
- Planning Meeting on August 31
  - Industries 4.0
    - Mr. Kawano/ Beckhoff Japan
    - Mr. Ogi /Mitsubishi UFJ Research and Consulting
    - Ms. Mashiro/ Tokyo Electron

## 2015 Critical Dates for SEMI Standards Ballots

	Ballot Submission Due Date	Voting Period Starts	Voting Period Ends
Cycle 7	August 17	August 31	September 30
Cycle 8	October 16	October 23	November 23
Cycle 9	November 16	December 1	December 31

<http://www.semi.org/Standards/Ballots>



# SEMI Standards Publications

Cycle	New	Revised	Reapproved	Withdrawn
January 2015	5	2	0	1
February 2015	3	7	3	0
March 2015	1	5	2	0
April 2015	3	2	0	0
May 2015	1	5	1	0
June 2015	4	3	15	0
July 2015	4	0	0	0
Aug 2015	3	9	8	0
Sept 2015	3	8	2	0

- Total SEMI Standards in portfolio: 947
  - Includes 113 Inactive Standards

# SEMI Standards Publications

## New Standards

Cycle	Designation	Title	Committee	Region
March 2015	SEMI 3D12	Guide for Measuring Flatness and Shape of Low Stiffness Wafers	3D-IC	NA
April 2015	SEMI C86	Guide for Ethylene Glycol	Liquid Chemicals	NA
April 2015	SEMI E173	Specification for XML SECS-II Message Notation (SMN)	Information & Control	NA
April 2015	SEMI PV55	Data Definition Specification for a Horizontal Communication Between Equipment for Photovoltaic Fabrication System	Automation Technology	EU
May 2015	SEMI C87	Test Method for Determining Roughness of Polymer Surfaces Used in Ultrapure Water and Liquid Chemical Distribution Systems by Contact Profilometry	Liquid Chemicals	NA

# SEMI Standards Publications

## New Standards Cont.

Cycle	Designation	Title	Committee	Region
June 2015	SEMI 3D I4	Guide for Incoming/Outgoing Quality Control and Testing Flow for 3DS-IC Products	3D-IC	TA
June 2015	SEMI HB5	Test Method for Measurement of Saw Marks on Crystalline Sapphire Wafers by Using Optical Probes	HB-LED	NA
June 2015	SEMI HB6	Test Method for Measurement of Thickness and Shape of Crystalline Sapphire Wafers by Using Optical Probes	HB-LED	NA
June 2015	SEMI HB7	Test Method for Measurement of Waviness of Crystalline Sapphire Wafers by Using Optical Probes	HB-LED	NA



# SEMI Standards Publications

## New Standards Cont.

Cycle	Designation	Title	Committee	Region
July 2015	SEMI 3D13	Guide for Measuring Voids in Bonded Wafer Stacks	3D-IC	NA
July 2015	SEMI PV64	Test Method for Determining B, P, Fe, Al, Ca Contents in Silicon Powder for PV Applications by Inductively Coupled Plasma Optical Emission Spectrometry	PV	C
July 2015	SEMI PV65	Test Method Based on RGB for Crystalline Silicon (C-Si) Solar Cell Color	PV	C
July 2015	SEMI PV66	Test Method for Determining the Aspect Ratio of Solar Cell Metal Fingers by Confocal Laser Scanning Microscope	PV	C






# SEMI Standards Publications

## New Standards Cont.

Cycle	Designation	Title	Committee	Region
August 2015	SEMI PV67	Test Method for the Etch Rate of a Crystalline Silicon Wafer by Determining the Weight Loss	PV	C
August 2015	SEMI PV68	Test Method for the Wire Tension of Multi-Wire Saws	PV	C
August 2015	SEMI C88	Specification for Dimensions of Sandwich Components for 1.125 Inch Type Surface Mount Gas Distribution Systems	GASES	NA

<http://ams.semi.org/ebusiness/standards/StandardsPublicationsList.aspx>

# A&R Ballot Review

A&R Cycle	Result	Notes
February 2015	 A&R Feb 2015	
March 2015	 A&R Mar 2015	
May 2015	 A&R May 2015	<p>Documents failed</p> <p>5621B: (NA Liquid Chemical) due to the lack of SNARF revision and no legitimate consideration of the negatives.</p> <ul style="list-style-type: none"> <li>• Subtype changed from Test Method to Guide without SNARF revision/approval</li> <li>• Normative statements from Test Method retained</li> <li>• Negatives found not persuasive based on inappropriate application of PM 2.11.3.1.6</li> </ul> <p>5816: (NA Gases) due to not correcting the non-conforming title</p> <ul style="list-style-type: none"> <li>• It was not balloted for a title change from a non-conforming title</li> </ul>
July 2015	 A&R July 2015	
August 2015	 A&R August 2015	



# Committee Staff Reports – new content

- Published Standards due for 5-year review
- 3-year SNARF project period
  - Regs § 8.3
- Nonconforming titles
  - Procedure Manual Appendix 4

# New Requirements/Process Reminders for TC Chapter Meetings [1/2]

- Standards Document Development Project Period
  - Project period shall not exceed 3 years (Regs 8.3.2)
    - SNARF approval to TC Chapter approval
  - If document development activity is found to be continuing, but cannot be completed with the project period, TC Chapter may grant one-year extension at a time, as many times as necessary.
  - The TC Chapter should review the expiration dates for all applicable SNARFs at each TC Chapter meeting. (PM Note 10)
- SNARF Review Period
  - A submitted SNARF for a new, or for a major revision to an existing, Standard or Safety Guideline is made available to all members of a TC Chapter's parent global technical committee for two weeks for their review and comment. (Regs 8.2.1)
    - If the SNARF is submitted at a TC Chapter meeting, the committee can review and approve, but the SNARF will need to be distributed for two weeks and then approved via GCS.
- New SNARF & TFOF Form



Microsoft Word  
7 - 2003 Document



Microsoft Word  
7 - 2003 Document

# New Requirements/Process Reminders for TC Chapter Meetings [2/2]

- Procedures for Correcting Nonconforming Titles of Published Standards Document (PM Appendix 4)
  - Some Standards qualify for a special procedure where a line item change can be used to correct the titles. Otherwise, the corrective action will likely require a major revision.



## ⇒ 5 Year Review



## ➤ Nonconforming Titles

- Refer to Procedure Manual (PM) Appendix Table A4-1 for details on nonconforming titles

## ⇒ SNARF 3 year status

- TC Chapter may grant a one-year extension

# Staff Contact Information from Sept 1, 2015

Committee	Staff
Gases, Facilities, FPD M&C, FPD Meteorology, Liquid Chemical SIG: SEA, CGMG	<i>Naoko Tejima</i> <i>Manager, Standards &amp; EHS</i> <a href="mailto:ntejima@semi.org">ntejima@semi.org</a>
PI&C, I&C, Metrics, Traceability, PV, PV Materials, Packaging, 3DS-IC	<i>Chie Yanagisawa</i> <i>Sr. Coordinator, Standards &amp; EHS</i> <a href="mailto:cyanagisawa@semi.org">cyanagisawa@semi.org</a>
JRSC, SPI TF, Compound, Micropatterning, Silicon Wafer, EHS, AT, Test, EHS SIG: ESG, SMG, EHS	<i>Junko Collins</i> <i>Director, Standards &amp; EHS</i> <a href="mailto:jcollins@semi.org">jcollins@semi.org</a>
Others	Staff
Standards Products General Information, SEMIViews	<i>C. Yanagisawa</i>
Other Standards Operation,	<i>J. Collins</i>